

# PRODUCT/PROCESS CHANGE NOTIFICATION

PCN APG-BAD/12/7242 Notification Date 05/04/2012

TO-220: Conversion from Tin dipping to Tin plating Leadframe

#### Table 1. Change Implementation Schedule

| Forecasted implementation date for change   | 01-Oct-2012 |
|---|-------------|
| Forecasted availabillity date of samples for customer   | 27-Apr-2012 |
| Forecasted date for <b>STMicroelectronics</b><br>change Qualification Plan results availability | 27-Apr-2012 |
| Estimated date of changed product first shipment  | 15-Oct-2012 |

#### Table 2. Change Identification

| Product Identification<br>(Product Family/Commercial Product) | See enclosed   |
|---|--|
| Type of change  | Package assembly process change  |
| Reason for change   | Process Razionalization  |
| Description of the change                                     | Due to process rationalization we are going to dismiss current Tin (Sn)<br>dipping leadframe process and implement Tin (Sn) plating process on<br>VIPower products housed in TO-220 package. |
| Product Line(s) and/or Part Number(s)                         | See attached   |
| Description of the Qualification Plan                         | See attached   |
| Change Product Identification                                 | Datacode   |
| Manufacturing Location(s)                                     | 1]St Shenzhen -China   |

#### Table 3. List of Attachments

| Customer Part numbers list |  |
|----------------------------|--|
| Qualification Plan results |  |

| Customer Acknowledgement of Receipt                       | PCN APG-BAD/12/7242          |
|---|------------------------------|
| Please sign and return to STMicroelectronics Sales Office | Notification Date 05/04/2012 |
| Qualification Plan Denied                                 | Name:                        |
| Qualification Plan Approved                               | Title:                       |
|   | Company:                     |
| 🗖 Change Denied   | Date:                        |
| Change Approved   | Signature:                   |
| Remark  |                              |
|   |                              |
|   |                              |
|   |                              |
|   |                              |
|   |                              |
|   |                              |
|   |                              |
|   |                              |
|   |                              |

| Name               | Function                   |
|--------------------|----------------------------|
| Liporace, Nicola   | Division Marketing Manager |
| Nicoloso, Riccardo | Division Product Manager   |
| Minerva, Francesco | Division Q.A. Manager      |

### **DOCUMENT APPROVAL**



### TO-220: Conversion from Tin dipping to Tin plating leadframe

- **WHAT:** Due to process rationalization we are going to dismiss current Tin (Sn) dipping leadframe process and implement Tin (Sn) plating process on VIPower products housed in TO-220 package.
- **WHY:** Process rationalization.
- WHO: All Customers using VIPower products housed in TO-220 package.

#### WHEN:

- Samples availability on demand.
- Qualification report: Reliability report QP000512CT2235 enclosed.
- Start conversion: from October 2012 onward.

WHERE: ST Shenzhen Assembly Plant.



## TO220 package

## Tin dipping to Tin plating conversion

| General Information        |              | Locations |                          |   |
|----------------------------|--------------|-----------|--------------------------|---|
| Product Line               | VN29         |           | Diffusion fab location   | S |
| Commercial Product         | VNP20N07-E   |           | Assembly plant location  | S |
| Silicon process technology | VIPower M0_2 |           | Test plant location      | S |
| Package                    | TO220        |           | Reliability lab location | S |

| General Information        |              |  |  |
|----------------------------|--------------|--|--|
| Product Line               | VN28         |  |  |
| Commercial Product         | VNP10N06-E   |  |  |
| Silicon process technology | VIPower M0_2 |  |  |
| Package                    | TO220        |  |  |

| Locations                |                        |  |  |
|--------------------------|------------------------|--|--|
| Diffusion fab location   | ST CT6 Catania (Italy) |  |  |
| Assembly plant location  | ST Shenzhen (China)    |  |  |
| Test plant location      | ST Shenzhen (China)    |  |  |
| Reliability lab location | ST Catania (Italy)     |  |  |

ST CT6 Catania (Italy) ST Shenzhen (China)

ST Shenzhen (China) ST Catania (Italy)

| General Information        |              |  |  |
|----------------------------|--------------|--|--|
| Product Line               | VN78         |  |  |
| Commercial Product         | VNP14NV04-E  |  |  |
| Silicon process technology | VIPower M0_3 |  |  |
| Package                    | TO220        |  |  |

| Locations                |                        |  |  |
|--------------------------|------------------------|--|--|
| Diffusion fab location   | ST CT6 Catania (Italy) |  |  |
| Assembly plant location  | ST Shenzhen (China)    |  |  |
| Test plant location      | ST Shenzhen (China)    |  |  |
| Reliability lab location | ST Catania (Italy)     |  |  |

Author: A.Marmoni QA and Qualification Section Mng APG Q&R Catania



### Automotive Product Group Automotive Electronic Division Reliability Qualification plan

### - 1. Reliability evaluations overview

In order to qualify for the package TO220 a conversion from Tin dipping to Tin plating 3 products were chosen as test vehicles that are the VNP20N07-E and the VNP10N06-E designed in VIPower M02 technology, the VNP14NV04-E designed in VIPower M03 technology. These products are diffused in ST CT6 Catania (Italy) 6" diffusion fab and assembled in ST Shenzhen (China) in TO220 package.

The qualification will be based using one lot per each chosen vehicle and according to the **AEC\_Q100 Rev.G** specification for the Accelerated Environment Stress (test Group A) the following tests will be performed for each lot: Preconditioning (PC), Temperature Humidity Bias (THB), Autoclave (AC), Thermal Cycling (TC), Power Temperature Cycling (PTC), High Temperature Storage (HTS). A Wire Bond Pull (WBP) and the Solderability (SD) analyses as Package Assembly Integrity (test Group C) will be also done.

| AEC<br># | Test Name   | STM Test Conditions   | Sample Size/<br>Lots  | Results<br>Fails/SS/Lots | Comments |
|----------|---|---|---|--------------------------|----------|
| A1       | PC<br>Pre Cond  | Preconditioning according to level Jedec JESD22-A113F Reflow according to Jedec JSTD020D-1              | Before THB, AC, TC, PTC.<br>Reliability executed on units soldered on PCB |                          |          |
| A2       | <b>THB</b><br>Temp<br>Humidity<br>Bias  | Ta=85°C, RH=85%, Vcc=5V,<br>Vs=16V for 1000 hours   | 77/3  |                          |          |
| A3       | AC<br>Autoclave<br>performed<br>by means<br>ENV. SEQ.<br>Enviromental<br>Sequence | <b>TC</b> (Ta=-65°C / +150°C for 100<br>cycles) +<br><b>AC</b> (Ta=121°C, Pa=2atm for 96<br>hours)      | 77/3  |                          |          |
| A4       | <b>TC</b><br>Temp.<br>Cycling   | Ta=-65ºC / +150ºC for 500 cycles  | 77/3  |                          |          |
| A5       | <b>PTC</b><br>Power<br>Temp.<br>Cycling   | Per JA105. Ta=-40°C / +125°C for<br>1000 cycles. Test before and after<br>at room and hot temperatures. | 45/1  |                          |          |
| A6       | HTSL<br>High Temp.<br>Storage Life  | Ta=150°C for 1000 hours. TST before and after at room and hot temperatures.                             | 45/3  |                          |          |
| C2       | <b>WBP</b><br>Wire Bond<br>Pull   | Per MIL-STD883, M2011 Condition<br>C or D. 0 and Ppk >= 1.66 or Cpk<br>>= 1.33                          | 30 bonds from<br>minimum 5 of<br>units from 1<br>lot                      |                          |          |
| C3       | <b>SD</b><br>Solderability  |   | 15/1  |                          |          |

#### Please Read Carefully:

Information in this document is provided solely in connection with ST products. STMicroelectronics NV and its subsidiaries("ST") reserve the right to make changes, corrections, modifications or improvements, to this document, and the products and services described herein at any time, without notice.

All ST products are sold pursuant to ST's terms and conditions of sale.

Purchasers are solely responsible for the choice, selection and use of the ST products and services described herein, and ST assumes no liability whatsoever relating to the choice, selection or use of the ST products and services described herein.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted under this document. If any part of this document refers to any third party products or services it shall not be deemed a license grant by ST for the use of such third party products or services, or any intellectual property contained therein or considered as a warranty covering the use in any manner whatsoever of such third party products or services or services or any intellectual property contained therein.

UNLESS OTHERWISE SET FORTH IN ST'S TERMS AND CONDITIONS OF SALE ST DISCLAIMS ANY EXPRESS OR IMPLIED WARRANTY WITH RESPECT TO THE USE AND/OR SALE OF ST PRODUCTS INCLUDING WITHOUT LIMITATION IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE (AND THEIR EQUIVALENTS UNDER THE LAWS OF ANY JURISDICTION), OR INFRINGEMENT OF ANY PATENT, COPYRIGHT OR OTHER INTELLECTUAL PROPERTY RIGHT.

UNLESS EXPRESSLY APPROVED IN WRITING BY AN AUTHORIZED ST REPRESENTATIVE, ST PRODUCTS ARE NOT RECOMMENDED, AUTHORIZED OR WARRANTED FOR USE IN MILITARY, AIR CRAFT, SPACE, LIFE SAVING, OR LIFE SUSTAINING APPLICATIONS, NOR IN PRODUCTS OR SYSTEMS WHERE FAILURE OR MALFUNCTION MAY RESULT IN PERSONAL INJURY, DEATH, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE. ST PRODUCTS WHICH ARE NOT SPECIFIED AS "AUTOMOTIVE GRADE" MAY ONLY BE USED IN AUTOMOTIVE APPLICATIONS AT USER'S OWN RISK.

Resale of ST products with provisions different from the statements and/or technical features set forth in this document shall immediately void any warranty granted by ST for the ST product or service described herein and shall not create or extend in any manner whatsoever, any liability of ST.

ST and the ST logo are trademarks or registered trademarks of ST in various countries.

Information in this document supersedes and replaces all information previously supplied.

The ST logo is a registered trademark of STMicroelectronics. All other names are the property of their respective owners

© 2012 STMicroelectronics - All rights reserved.

STMicroelectronics group of companies

Australia - Belgium - Brazil - Canada - China - Czech Republic - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan -Malaysia - Malta - Morroco - Singapore - Spain - Sweden - Switzerland - United Kingdom - United States of America

www.st.com